ON Semiconductor®



STR-NIS5820-GEVB: Strata Enabled NIS5820 12V, 24mQ, 8A eFuse

The STR-NIS5820-GEVB provides an evaluation board for the NIS5820 eFuse within the Strata Development Environment. The NIS5820 offers a programmable trip current limit, a programmable slew rate, and thermal protection features. The evaluation board provides an on board short circuit load to test the short circuit protection features of the eFuse. This evaluation board must be used with Strata to control the eFuse and monitor telemetry such as input/output voltage, input/output current, and temperature.



Features and Applications

Features

- Multiple overload current options
- 2 independently controlled eFuses that can be placed in parallel
- Vin Range from 9.2V to 18V
- Programmable slew rate

Applications

- Hard Drives
- Servers
- Motherboards
- Fan Drives

Evaluation/Development Tool Information				
Product	Status	Compliance	Short Description	Parts Used
STR-NIS5820-GEVB	Active	Pb-free	Strata Enabled NIS5820 12V, 24m Ω , 8A eFuse	NIS5820MT1TXG

https://www.onsemi.com/support/evaluation-board/str-nis5820-gevb/2-11-20